INTERNATIONAL SEARCH REPORT

Intermonal Application No PCT/IB2005/050343

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A. CLASSIFICATION OF SUBJECT MATTER IPC 7 G01R31/30 G01R31/3161 G01R31/3167									
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X F	urther documents are listed in the continuation of box C.	X Patent family members are liste	ed in annex.						
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29 April 2005		10/05/2005							
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